Electronic supplementary information

Synthesis and Photoresponse of Novel Cu₂CdSnS₄ Semiconductor Nanorods[†]

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Experimental section

I. Chemicals

Copper monochloride (CuCl, AR), tin dichloride hydrated (SnCl₂·2H₂O, AR), cadmium acetate dihydrate (Cd (CH₃COO)₂·2H₂O, AR), carbon disulfide(CS₂, AR), 3-mercaptopropionic acid (HSCH₂CH₂CO₂H, 98%), hexylamine (CH₃(CH₂)₅NH₂, 99%) were purchased from Aladdin inc. All chemical reagents were used as received without any further purification.

II. Synthesis of Cu₂CdSnS₄ Nanorods.

1.0 mmol CuCl, 0.5 mmol SnCl₂·2H₂O, 0.5 mmol Cd(CH₃COO)₂·2H₂O were dissolved in 12.0 mL of hexylamine by ultrasound in 50mL conical flask. 12.0 mL of hexylamine was loaded into another 50 mL conical flask. Afterwards, 1.0 mL of carbon disulfide and 1.0 mL of 3-mercaptopropionic were slowly added into the conical flask in an ice water bath, respectively. The former solution was slowly added into the later solution. Subsequently, 1.0 mL of 3-mercaptopropionic was added into the solution. After 12 h continuously vigorous stirring, the solution was transferred into 40 mL Teflon-lined stainless steel autoclave and solvothermal reaction at 140°C for 25 min then rise to 180°C and keep at this temperature for 2 h. Finally, the

autoclave was naturally cooled to room temperature. The nanocrystals were isolated by precipitation with 20 mL of methanol followed by centrifugation at 4000 rpm for 5 min. The purified nanocrystals were re-dispersed in chloroform for TEM and XRD measurements.

III. Characterization

The powder XRD pattern was recorded using a Bruker D8 X-ray diffractometer. Energy Disperse Spectroscopy (EDS) spectrum was obtained by using a scanning electron microscope (Hitachi S-4800) equipped with a Bruker AXS XFlash detector 4010. Transmission electron microscopy (TEM) and selected area electron diffraction (SAED) images were taken on a FEI Tecnai G2 F20 electron microscope with an accelerating voltage of 200 kV. UV-vis-NIR absorption spectrum was measured by metash UV-5200 spectrophotometer. X-ray photoelectron spectra (XPS) were measured with VG ESCALAB MK (VG Company, UK) at room temperature by using a Mg K α X-ray source (*hV*=1253.6 eV) at 14 kV and 20 mA. The optoelectronic properties were carried out by spin casting 2.0 mL of concentrated nanocrystals solution in chloroform onto a glass slide (2*2cm). Annealing process was conducted at 400 in the glove-box under N₂ atmosphere in order to remove ligands and solvent. Current-voltage characteristics were tested using a Keithley 2400 source meter under AM 1.5G solar simulator (Abet inc. Sun 2000) that had an intensity of 100 mW/cm². The scanning voltage was tuned from -5V to 5 V.

Figure S1. Unit cell of wurtzite Cu₂CdSnS₄



hkl	Observed 20	Simulated 20	$\Delta 2\theta$
100	26.472	26.479	-0.007
002	27.890	27.884	+0.006
101	29.989	29.974	+0.015
102	38.908	38.827	+0.081
110	46.731	46.736	-0.005
103	50.596	50.634	-0.038
112	55.298	55.299	-0.001

Table S1. Comparison of experimental and simulated XRD peaks for wurtzite Cu_2CdSnS_{4} .

Crystal data

Formula	Cu_2CdSnS_4
Crystal system	Wurtzite
Space group	<i>P</i> 6 ₃ mc (No. 186)
Unit cell dimensions	a = b = 3.8847 Å, $c = 6.3926$ Å

Atomic coordinates

Atom	Wyck.	x/a	y/b	z/c
S	2b	1/3	2/3	0
Sn	2b	1/3	2/3	0.3752
Cd	2b	1/3	2/3	0.3752
Cu	2b	1/3	2/3	0.3752

Note that Cu^+ , Cd^{2+} , and Sn^{4+} ions occupy the same position, and the occupancy possibilities of Cu⁺, Cd²⁺, and Sn⁴⁺ are 1/2, 1/4 and 1/4, respectively.

Figure S2. EDS spectrum of wurtzite Cu₂CdSnS₄ nanorods



Figure S3. TEM image of wurtzite Cu₂CdSnS₄ nanorods with low density



Figure S4. Size distribution of wurtzite Cu₂CdSnS₄ nanorods (a: length distribution; b: diameter distribution)



